uc3m Universidad Carlos III de Madrid

Advanced sensors and measurements techniques

Academic Year: (2022 / 2023) Review date: 20-05-2022

Department assigned to the subject: Electronic Technology Department

Coordinating teacher: ACEDO GALLARDO, PABLO

Type: Compulsory ECTS Credits: 3.0

Year: 6 Semester: 1

REQUIREMENTS (SUBJECTS THAT ARE ASSUMED TO BE KNOWN)

Electromagnetism and Optics

Solid State Fundamentals for Engineering

Electronic Engineering Fundamentals

Statistical Physics

Instrumentation and Measurements

Photonics

OBJECTIVES

To know the fundamentals behind MEMS and MOEMS based sensors, as well as the latest developments in new materials and manufacturing processes for sensors, and their field of application.

To know the fundamentals of microfluidic systems and their use in instrumentation and measurement systems in biomedical and biological environments.

To know various instruments and experimental techniques of general use in research and development of devices and instruments of high added value: microscopy and spectroscopy among others.

DESCRIPTION OF CONTENTS: PROGRAMME

1.- MEMS. Microelectromechanical Systems

Introduction. Scaling laws.

Microsystems design fundamentals. Examples.

MEMS Sensors examples and applications

2.- Optical MEMS (MOEMS).

Introduction and classification.

Micromirror-based devices and scanning applications

MOEMS for signal processing and communications

3.-Microfabrication processes and techniques for MEMS and other sensors.

Bulk micromaching

Surface micromachining

Additive manufacturing of microstructures.

4.-New materials and components for sensors.

Organic electronics and photonics.

Flexible electronics

Surface functionalization and biosensors.

5.-Microfluidic Sensors.

Revision: microfluidics fundamentals and components

Microfluidic Sensors examples

Lab-on-a-chip and organ-on-a-chip

6.-Advanced instrumentation and experimental techniques

Optical microscopy, fluorescence microscopy and confocal microscopy.

Spectroscopy

LEARNING ACTIVITIES AND METHODOLOGY

AF1. THEORETICAL-PRACTICAL CLASSES.

AF3. STUDENT INDIVIDUAL WORK OR GROUP WORK.

AF8. WORKSHOPS AND LABORATORY SESSIONS.

AF9. FINAL EXAM.

MD1. THEORY CLASS.

MD2. PRACTICAL CLASS.

ASSESSMENT SYSTEM

SE1. FINAL EXAM. 50%.

SE2. CONTINUOUS EVALUATION.

Partial exam: 30% Laboratory: 20%

% end-of-term-examination:	50
% of continuous assessment (assignments, laboratory, practicals):	50

BASIC BIBLIOGRAPHY

- Liu C. Foundations of MEMS. Second Edition, Prentice Hall , 2012

ADDITIONAL BIBLIOGRAPHY

- Kaajakari V. Practical MEMS, Small Gear Publising, 2009
- Tkachenko N.V. Optical Spectroscopy. Methods and Instrumentations, Elsevier, 2006